DEFENSE LOGISTICS AGENCY
LAND AND MARITIME
POST OFFICE BOX 3990
COLUMBUS, OH 43218-3990

June 3, 2024

Mr. Harrison Betz
Quality Engineering
Analog Devices, Inc.
4200 NW Pacific Rim Blvd
Camas, WA 98607

Dear Mr. Betz:

Re: Lab Suitability for MIL-STD-883, FSC 5962; VQC-24-0387754; CN: 087845

Effective immediately, the previous Lab Suitability Letter issued to Analog Devices, Inc. by the DLA Land and Maritime, is suspended by this letter.

Analog Devices, Inc. (ADI) has demonstrated to the DLA Land and Maritime compliance with MIL-STD-883, the test standard for integrated circuits. ADI is granted laboratory suitability, effective on the date of this letter, for the facilities, test methods and conditions shown on the enclosure. All testing must be performed in accordance with MIL-PRF-38535 and MIL-STD-883 test methods.

This letter is issued in conjunction with the QML certification letter DLA Land and Maritime VQC-24-038774 and supersedes the previous laboratory suitability letter DLA Land and Maritime VQC-23-037734.

This Laboratory Suitability is subject to the policies, procedures, and conditions of the Defense Standardization Program, as published in the manual DoD 4120.24-M and SD-6.

If you have any questions, please contact Mr. Scott Thomas at (614) 692-0587.

Sincerely,
ADAMS.MICHAEL.S.1230230427
Digitally signed by ADAMS.MICHAEL.S.1230230427
Date: 2024.06.06 10:17:11 -04'00'
MICHAEL S. ADAMS
Chief
Custom Devices Branch

Enclosures

Enclosure VQC-24-038775

TEST	METHOD/ CONDITIONS	ADPhils	OTHERS
Electrical Test	Paragraph 4.5	X	
Moisture Resistance	1004	X	Micross
Steady State Life	1005 A - E	X	Team Quest, TSSI
Salt Atmosphere	1009 A	X	Micross
Temperature Cycle	1010 C	X	ADPen, Micross
Thermal Shock	1011 B	X	Micross
Seal	1014	A1, A2, C1	Micross
Burn-In	1015 A, B, C, D, E	X	Team Quest, TSSI
Internal Water Vapor	1018		Oneida I
Ionizing Radiation (Total Dose)	1019 A, D		VPT
Constant Acceleration	2001 D, E (Y1 only)	X	Micross
Mechanical Shock	2002 B	X	Micross, Oneida II
Solderability	2003 / J-STD-002	X	Micross
Lead Integrity	2004 B2, D	X	Micross
Vibration, Variable Freq	2007 A	X	Micross, Oneida II
External Visual	2009	X	
Internal Visual (monolithic)	2010 A, B	X	ADPen
Bond Strength	2011 D	X	ADPen
Radiography	2012		ADPen, NDT
Internal Visual for DPA	2013	X	
Internal Visual & Mechanical	2014	X	
Resistance to Solvents	2015	X	ADPen
Physical Dimensions	2016	X	Micross, NDT
SEM	2018 B1		ADI Camas, ADLK, ADWIL
Die Shear Strength	2019	X	ADPen
Particle Impact Noise Detect	2020 A	X	
Glassivation Layer Integrity	2021 A		ADLK, ADWIL
Nondestructive Bond Pull	2023	X	
Lid Torque	2024	X	
Adhesion of Lead Finish	2025	X	Micross
Lead Integrity	2028		Micross
Ultrasonic Inspection of Die Attach	2030		ADPen
ESD Sens. Classification	3015	X	
Resistance to Soldering Heat	2036 I, J, K	X	

ADLK – ADI Limerick, Ireland

ADPen – ADI Penang, Malaysia

ADPhils – ADI Philippines

ADWIL – ADI Wilmington, MA

Micross - Micross STS – Milpitas, CA

NDT - NDT Laboratories – Sunnyvale, CA

Oneida I – Oneida Research Services Inc - Whitesboro. NY

Oneida II - Oneida Research Services Inc – Reading, PA

Team Quest & TSSI – Cavite, Philippines
VPT - VPT Rad – Chelmsford, MA